



RADIO TEST REPORT

Test Report No. : 12541448H-R1

Applicant : Panasonic Corporation of North America
Type of Equipment : RKE TXE
Model No. : IK3600F
FCC ID : ACJ9321K3600F
Test regulation : FCC Part 15 Subpart C: 2018
Test Result : Complied (Refer to SECTION 3.2)

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2. The results in this report apply only to the sample tested.
3. This sample tested is in compliance with the above regulation.
4. The test results in this report are traceable to the national or international standards.
5. This test report covers Radio technical requirements. It does not cover administrative issues such as Manual or non-Radio test related Requirements. (if applicable)
6. The all test items in this test report are conducted by UL Japan, Inc. Ise EMC Lab.
7. This test report must not be used by the customer to claim product certification, approval, or endorsement by NVLAP, NIST, or any agency of the Federal Government.
8. The information provided from the customer for this report is identified in SECTION 1.
9. This report is a revised version of 12541448H. 12541448H is replaced with this report.

Date of test: December 5, 2018

Representative test engineer:

Hiroyuki Furutaka
Engineer

Consumer Technology Division

Approved by:

Shinichi Miyazono
Engineer

Consumer Technology Division



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13-EM-F0429

REVISION HISTORY

Original Test Report No.: 12541448H

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SECTION 1: Customer information

Company Name	:	Panasonic Corporation of North America ^{*1)}
Address	:	Two Riverfront Plaza, 9th Floor Newark, NJ 07102-5490
Telephone Number	:	+1-201-348-7760
Facsimile Number	:	+1-201-348-7760
Contact Person	:	Ben Botros

The information provided from the customer is as follows;

- Applicant, Type of Equipment, Model No. on the cover and other relevant pages
- SECTION 1: Customer information
- SECTION 2: Equipment under test (E.U.T.)
- SECTION 4: Operation of E.U.T. during testing

* The laboratory is exempted from liability of any test results affected from the information in SECTION 2 and 4.

*1) Panasonic Corporation of North America designates Panasonic Automotive Systems Asia Pacific Co.,Ltd as manufacturer of the product (RKE TXE).

SECTION 2: Equipment under test (E.U.T.)

2.1 Identification of E.U.T.

Type of Equipment	:	RKE TXE
Model No.	:	IK3600F
Serial No.	:	Refer to Section 4, Clause 4.2
Rating	:	DC 3.0 V
Receipt Date of Sample (Information from test lab.)	:	December 4, 2018
Country of Mass-production	:	Thailand
Condition of EUT	:	Production prototype (Not for Sale: This sample is equivalent to mass-produced items.)
Modification of EUT	:	No Modification by the test lab

2.2 Product Description

Model: IK3600F (referred to as the EUT in this report) is a RKE TXE.

Radio Specification

Radio Type	:	Transmitter
Frequency of Operation	:	433.92 MHz
Modulation	:	FSK
Antenna type	:	Copper printing monopole antenna
Clock frequency (Maximum)	:	27.6 MHz

SECTION 3: Test specification, procedures & results

3.1 Test Specification

Test Specification : FCC Part 15 Subpart C
FCC Part 15 final revised on March 12, 2018 and effective April 11, 2018

Title : FCC 47CFR Part15 Radio Frequency Device Subpart C Intentional Radiators
Section 15.231 Periodic operation in the band 40.66-40.70 MHz and above 70 MHz.

3.2 Procedures and results

Item	Test Procedure	Specification	Worst margin	Results	Remarks
Conducted emission	FCC: ANSI C63.10:2013 6 Standard test methods	FCC: Section 15.207	N/A *1)	N/A	-
	IC: RSS-Gen 8.8	IC: RSS-Gen 8.8			
Automatically Deactivate	FCC: ANSI C63.10:2013 6 Standard test methods	FCC: Section 15.231(a)(1)	N/A	Complied a)	Radiated
	IC: -	IC: RSS-210 A1.1			
Electric Field Strength of Fundamental Emission	FCC: ANSI C63.10:2013 6 Standard test methods	FCC: Section 15.231(b)	1.0 dB 433.920 MHz Horizontal PK with Duty factor	Complied# b)	Radiated
	IC: RSS-Gen 6.12	IC: RSS-210 A1.2			
Electric Field Strength of Spurious Emission	FCC: ANSI C63.10:2013 6 Standard test methods	FCC: Section 15.205 Section 15.209 Section 15.231(b)	1.3 dB 3905.280 MHz Vertical PK with Duty factor	Complied# c)	Radiated
	IC: RSS-Gen 6.13	IC: RSS-210 A1.2, 4.4 RSS-Gen 8.9			
-20dB Bandwidth	FCC: ANSI C63.10:2013 6 Standard test methods	FCC: Section 15.231(c)	N/A	Complied d)	Radiated
	IC: -	IC: Reference data			

Note: UL Japan, Inc.'s EMI Work Procedures No. 13-EM-W0420 and 13-EM-W0422.

*1) The test is not applicable since the EUT does not have AC Mains.

a) Refer to APPENDIX 1 (data of Automatically Deactivate)

b) Refer to APPENDIX 1 (data of Radiated Emission (Electric Field Strength of Fundamental and Spurious Emission))

c) Refer to APPENDIX 1 (data of Radiated Emission (Electric Field Strength of Fundamental and Spurious Emission))

d) Refer to APPENDIX 1 (data of -20dB and 99% Occupied Bandwidth)

Symbols:

Complied The data of this test item has enough margin, more than the measurement uncertainty.

Complied# The data of this test item meets the limits unless the measurement uncertainty is taken into consideration.

FCC 15.31 (e)

This test was performed with the New Battery (DC 3.0 V) during the tests. Therefore, the EUT complies with the requirement.

FCC Part 15.203 Antenna requirement

It is impossible for end users to replace the antenna, because the antenna is mounted inside of the EUT. Therefore, the equipment complies with the antenna requirement of Section 15.203.

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3.3 Addition to standard

Item	Test Procedure	Specification	Worst margin	Results	Remarks
99 % Occupied Bandwidth	IC: RSS-Gen 6.7	IC: RSS-210 A1.3	N/A	Complied	Radiated

Other than above, no addition, exclusion nor deviation has been made from the standard.

3.4 Uncertainty

There is no applicable rule of uncertainty in this applied standard. Therefore, the following results are derived depending on whether or not laboratory uncertainty is applied.

The following uncertainties have been calculated to provide a confidence level of 95 % using a coverage factor $k = 2$.

Polarity	Radiated emission (Below 1 GHz)			
	(3 m*)(+/-)		(10 m*)(+/-)	
	30 MHz to 200 MHz	200 MHz to 1000 MHz	30 MHz to 200 MHz	200 MHz to 1000 MHz
Horizontal	4.8 dB	5.2 dB	4.8 dB	5.0 dB
Vertical	5.0 dB	6.3 dB	4.9 dB	5.0 dB

Radiated emission (Above 1 GHz)				
(3 m*)(+/-)		(1 m*)(+/-)		(10 m*)(+/-)
1 GHz to 6 GHz	6 GHz to 18 GHz	10 GHz to 26.5 GHz	26.5 GHz to 40 GHz	1 GHz to 18 GHz
5.0 dB	5.3 dB	5.8 dB	5.8 dB	5.2 dB

* Measurement distance

Automatically Deactivate
0.10 %

Bandwidth
0.96 %

3.5 Test Location

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NVLAP Lab. code: 200572-0 / FCC Test Firm Registration Number: 199967

Test site	IC Registration Number	Width x Depth x Height (m)	Size of reference ground plane (m) / horizontal conducting plane	Other rooms	Maximum measurement distance
No.1 semi-anechoic chamber	2973C-1	19.2 x 11.2 x 7.7	7.0 x 6.0	No.1 Power source room	10 m
No.2 semi-anechoic chamber	2973C-2	7.5 x 5.8 x 5.2	4.0 x 4.0	-	3 m
No.3 semi-anechoic chamber	2973C-3	12.0 x 8.5 x 5.9	6.8 x 5.75	No.3 Preparation room	3 m
No.3 shielded room	-	4.0 x 6.0 x 2.7	N/A	-	-
No.4 semi-anechoic chamber	2973C-4	12.0 x 8.5 x 5.9	6.8 x 5.75	No.4 Preparation room	3 m
No.4 shielded room	-	4.0 x 6.0 x 2.7	N/A	-	-
No.5 semi-anechoic chamber	-	6.0 x 6.0 x 3.9	6.0 x 6.0	-	-
No.6 shielded room	-	4.0 x 4.5 x 2.7	4.0 x 4.5	-	-
No.6 measurement room	-	4.75 x 5.4 x 3.0	4.75 x 4.15	-	-
No.7 shielded room	-	4.7 x 7.5 x 2.7	4.7 x 7.5	-	-
No.8 measurement room	-	3.1 x 5.0 x 2.7	3.1 x 5.0	-	-
No.9 measurement room	-	8.8 x 4.6 x 2.8	2.4 x 2.4	-	-
No.11 measurement room	-	6.2 x 4.7 x 3.0	4.8 x 4.6	-	-

* Size of vertical conducting plane (for Conducted Emission test) : 2.0 m x 2.0 m for No.1, No.2, No.3, and No.4 semi-anechoic chambers and No.3 and No.4 shielded rooms.

3.6 Test data, Test instruments, and Test set up

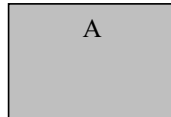
Refer to APPENDIX.

SECTION 4: Operation of E.U.T. during testing

4.1 Operating Mode(s)

Test Item*	Mode
Automatically Deactivate	Normal use mode
Electric Field Strength of Fundamental Emission Electric Field Strength of Spurious Emission -20 dB & 99 % Occupied Bandwidth	Transmitting mode (Tx) *1)
* The system was configured in typical fashion (as a user would normally use it) for testing. *1) End users cannot change the settings of the output power of the product.	

4.2 Configuration and peripherals



* Cabling and setup(s) were taken into consideration and test data was taken under worse case conditions.

Description of EUT

No.	Item	Model number	Serial number	Manufacturer	Remarks
A	RKE TXE	IK3600F	No.33 *1) No.18 *2)	Panasonic Automotive Systems Asia Pacific Co.,Ltd	EUT

*1) Used for Normal use mode

*2) Used for Transmitting mode

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SECTION 5: Radiated emission (Electric Field Strength of Fundamental and Spurious Emission)

Test Procedure and conditions

[For below 30 MHz]

The noise level was checked by moving a search-coil (Loop Antenna) close to the EUT.

[For 30 MHz to 1 GHz]

EUT was placed on a urethane platform of nominal size, 0.5 m by 1.0 m, raised 0.8 m above the conducting ground plane. The Radiated Electric Field Strength has been measured in a Semi Anechoic Chamber with a ground plane.

[For above 1 GHz]

EUT was placed on a urethane platform of nominal size, 0.5 m by 0.5 m, raised 1.5 m above the conducting ground plane.

The Radiated Electric Field Strength has been measured in a Semi Anechoic Chamber with absorbent materials lined on a ground plane.

The measuring antenna height was varied between 1 and 4 m and EUT was rotated a full revolution in order to obtain the maximum value of the electric field strength.

The measurements were performed for both vertical and horizontal antenna polarization.

The radiated emission measurements were made with the following detector function of the test receiver / spectrum analyzer.

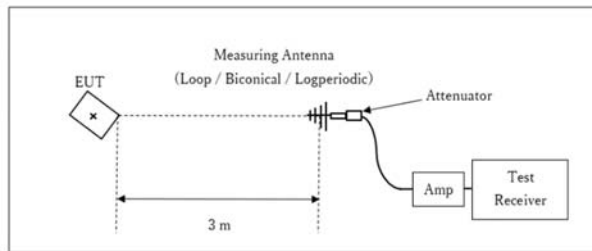
Test Antennas are used as below;

Frequency	Below 30 MHz	30 MHz to 200 MHz	200 MHz to 1 GHz	Above 1 GHz
Antenna Type	Loop	Biconical	Logperiodic	Horn

	From 9 kHz to 90 kHz and From 110 kHz to 150 kHz	From 90 kHz to 110 kHz	From 150 kHz to 490 kHz	From 490 kHz to 30 MHz	From 30 MHz to 1 GHz	Above 1 GHz
Detector Type	Peak	Peak	Peak	Peak	Peak and Peak with Duty factor	Peak and Peak with Duty factor
IF Bandwidth	200 Hz	200 Hz	9.0 kHz	9.0 kHz	120 kHz	PK: S/A: RBW 1 MHz, VBW: 3 MHz

[Test Setup]

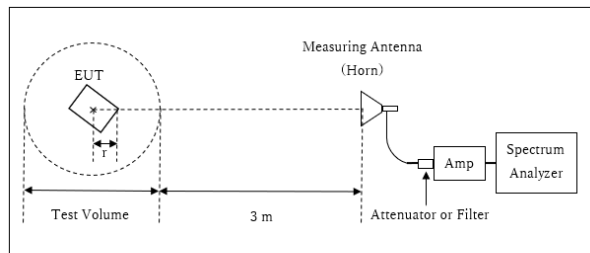
Below 1 GHz



x : Center of turn table

Test Distance: 3 m

1 GHz - 10 GHz



r : Radius of an outer periphery of EUT

x : Center of turn table

Distance Factor: $20 \times \log (4.0 \text{ m} / 3.0 \text{ m}) = 2.5 \text{ dB}$

* Test Distance: $(3 + \text{Test Volume} / 2) - r = 4.0 \text{ m}$

Test Volume : 2.0 m

(Test Volume has been calibrated based on CISPR 16-1-4.)

$r = 0.0 \text{ m}$

* The test was performed with $r = 0.0 \text{ m}$ since EUT is small and it was the rather conservative condition.

- The carrier level (or, noise levels) was (or were) measured at each position of all three axes X, Y and Z, and the position that has the maximum noise was determined.

Noise levels of all the frequencies were measured at the position.

*The result is rounded off to the second decimal place, so some differences might be observed.

Measurement range : 9 kHz - 4.4 GHz

Test data : APPENDIX

Test result : Pass

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SECTION 6: Automatically deactivate

Test Procedure

The measurement was performed with Electric field strength using a spectrum analyzer.

Test data : APPENDIX
Test result : Pass

SECTION 7: -20 dB and 99 % Occupied Bandwidth

Test Procedure

The test was measured with a spectrum analyzer using a test fixture.

Test	Span	RBW	VBW	Sweep	Detector	Trace	Instrument used
20 dB Bandwidth	150 kHz	1.5 kHz	5.1 kHz	Auto	Peak	Max Hold	Spectrum Analyzer
99 % Occupied Bandwidth	Enough width to display emission skirts	1 to 5 % of OBW	Three times of RBW	Auto	Peak	Max Hold	Spectrum Analyzer
Peak hold was applied as Worst-case measurement.							

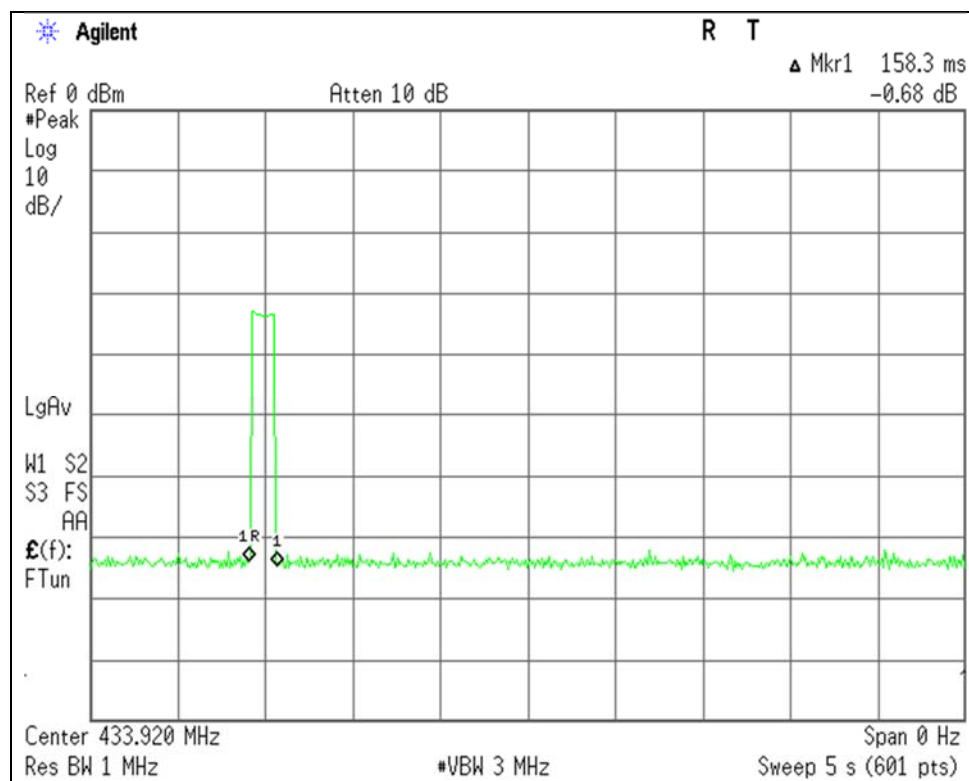
Test data : APPENDIX
Test result : Pass

APPENDIX 1: Test data

Automatically deactivate

Report No.	12541448H
Test place	Ise EMC Lab.
Semi Anechoic Chamber	No.4
Date	December 5, 2018
Temperature / Humidity	23 deg. C / 48 % RH
Engineer	Ryota Yamanaka
Mode	Normal use mode

Time of Transmitting [sec]	Limit [sec]	Result
0.1583	5.00	Pass



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Radiated Emission (Electric Field Strength of Fundamental and Spurious Emission)

Report No.	12541448H	
Test place	Ise EMC Lab.	
Semi Anechoic Chamber	No.4	No.4
Date	December 5, 2018 (Day)	December 5, 2018 (Night)
Temperature / Humidity	22 deg. C / 51 % RH	23 deg. C / 53 % RH
Engineer	Hiroyuki Furutaka (Above 1GHz)	Ryota Yamanaka (Below 1GHz)
Mode	Tx 433.92 MHz	

PK

Frequency [MHz]	Detector	Reading [dBuV]		Ant Factor [dB/m]	Loss [dB]	Gain [dB]	Duty Factor [dB]	Result [dBuV/m]		Limit [dBuV/m]	Margin [dB]		Remark Inside or Outside of Restricted Bands
		Hor	Ver					Hor	Ver		Hor	Ver	
433.920	PK	84.6	84.4	16.4	10.8	32.0	-	79.8	79.6	100.8	21.0	21.2	Carrier
867.840	PK	38.0	30.3	22.0	13.0	31.4	-	41.6	33.9	80.8	39.2	46.9	Outside
1301.760	PK	43.8	44.0	25.4	6.2	33.1	-	42.3	42.5	73.9	31.6	31.4	Inside
1735.680	PK	49.5	48.0	25.3	5.8	32.0	-	48.6	47.1	80.8	32.2	33.7	Outside
2169.600	PK	44.1	44.0	27.5	5.8	31.4	-	46.0	45.9	80.8	34.8	34.9	Outside
2603.520	PK	47.9	46.5	28.2	6.0	31.2	-	50.9	49.5	80.8	29.9	31.3	Outside
3037.440	PK	46.0	46.2	28.5	6.1	31.1	-	49.5	49.7	80.8	31.3	31.1	Outside
3471.360	PK	45.1	44.9	29.0	6.3	30.9	-	49.5	49.3	80.8	31.3	31.5	Outside
3905.280	PK	47.0	47.2	29.7	6.4	30.7	-	52.4	52.6	73.9	21.5	21.3	Inside
4339.200	PK	45.5	45.0	30.4	6.7	30.7	-	51.9	51.4	73.9	22.0	22.5	Inside

PK with Duty factor

Frequency [MHz]	Detector	Reading [dBuV]		Ant Factor [dB/m]	Loss [dB]	Gain [dB]	Duty Factor [dB]	Result [dBuV/m]		Limit [dBuV/m]	Margin [dB]		Remark
		Hor	Ver					Hor	Ver		Hor	Ver	
433.920	PK	84.6	84.4	16.4	10.8	32.0	0.0	79.8	79.6	80.8	1.0	1.2	Carrier
867.840	PK	38.0	30.3	22.0	13.0	31.4	0.0	41.6	33.9	60.8	19.2	26.9	Outside
1301.760	PK	43.8	44.0	25.4	6.2	33.1	0.0	42.3	42.5	53.9	11.6	11.4	Inside
1735.680	PK	49.5	48.0	25.3	5.8	32.0	0.0	48.6	47.1	60.8	12.2	13.7	Outside
2169.600	PK	44.1	44.0	27.5	5.8	31.4	0.0	46.0	45.9	60.8	14.8	14.9	Outside
2603.520	PK	47.9	46.5	28.2	6.0	31.2	0.0	50.9	49.5	60.8	9.9	11.3	Outside
3037.440	PK	46.0	46.2	28.5	6.1	31.1	0.0	49.5	49.7	60.8	11.3	11.1	Outside
3471.360	PK	45.1	44.9	29.0	6.3	30.9	0.0	49.5	49.3	60.8	11.3	11.5	Outside
3905.280	PK	47.0	47.2	29.7	6.4	30.7	0.0	52.4	52.6	53.9	1.5	1.3	Inside
4339.200	PK	45.5	45.0	30.4	6.7	30.7	0.0	51.9	51.4	53.9	2.0	2.5	Inside

Sample calculation:

Result of PK = Reading + Ant Factor + Loss {Cable + Attenuator + Filter (above 1GHz) + Distance factor (above 1 GHz)} - Gain (Amplifier)

Result of PK with Duty factor = Reading + Ant Factor + Loss {Cable + Attenuator + Filter (above 1 GHz) + Distance factor (above 1 GHz)} - Gain (Amplifier) + Duty factor (Refer to Duty factor data sheet)

For above 1GHz : Distance Factor: $20 \times \log(4.0 \text{ m}/3.0 \text{ m}) = 2.50 \text{ dB}$

*Other frequency noises omitted in this report were not seen or had enough margin (more than 20dB).

Since the peak emission result satisfied the average limit, duty factor was omitted.

Although Duty of this product was 100% or less, the result of AV (PK with Duty factor) was calculated by applying Duty 100% as worst.

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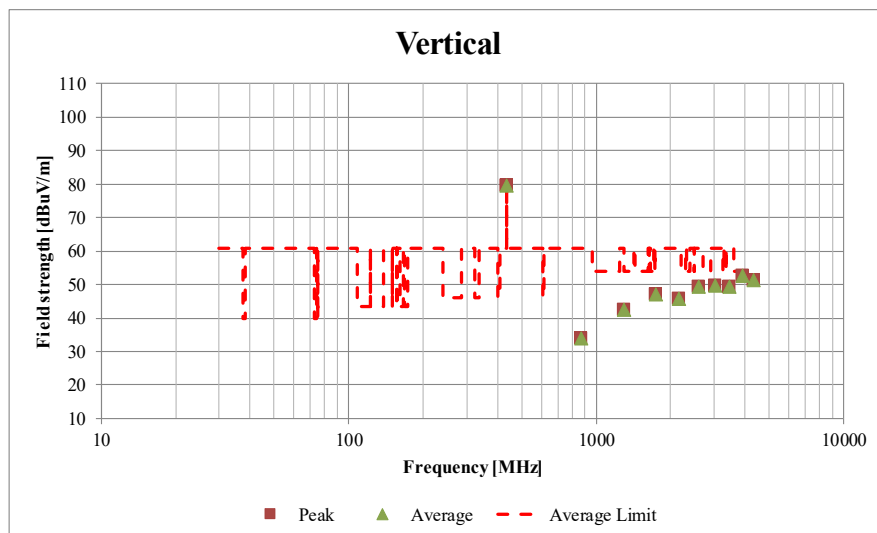
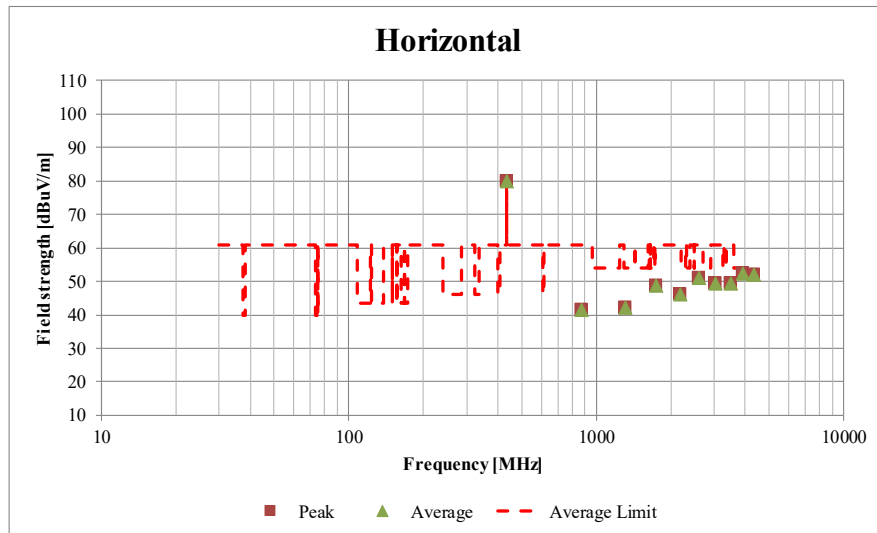
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Radiated Spurious Emission
(Plot data, Worst case)

Report No.	12541448H	
Test place	Ise EMC Lab.	
Semi Anechoic Chamber	No.4	No.4
Date	December 5, 2018 (Day)	December 5, 2018 (Night)
Temperature / Humidity	22 deg. C / 51 % RH	23 deg. C / 53 % RH
Engineer	Hiroyuki Furutaka (Above 1GHz)	Ryota Yamanaka (Below 1GHz)
Mode	Tx 433.92 MHz	



*These plots data contains sufficient number to show the trend of characteristic features for EUT.

-20dB and 99% Occupied Bandwidth

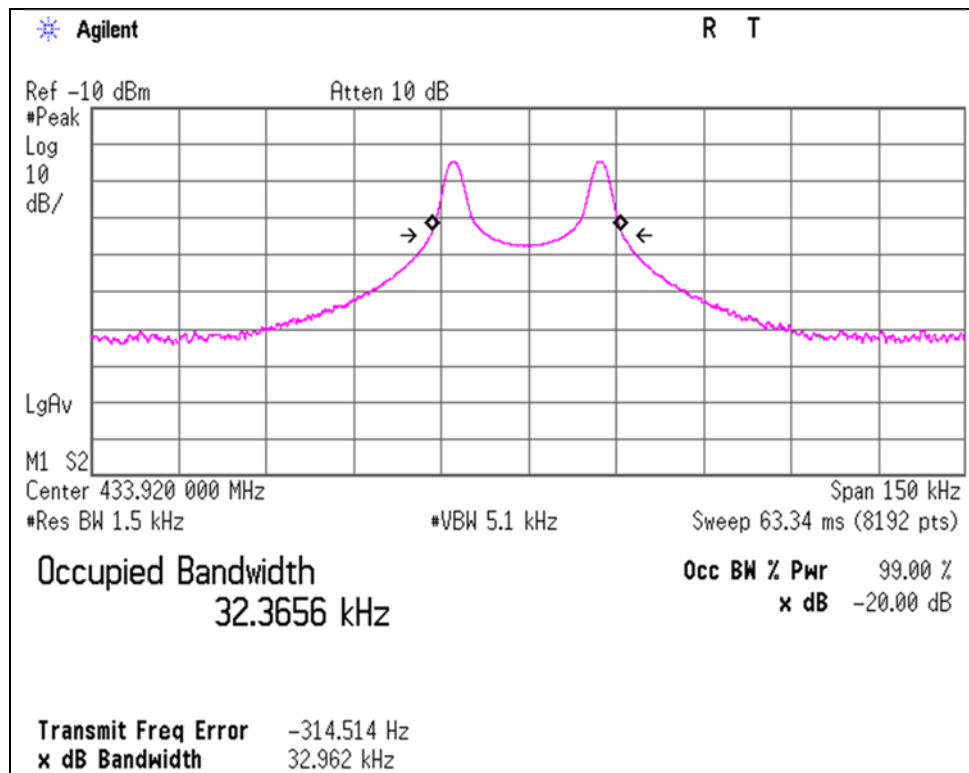
Report No.	12541448H
Test place	Ise EMC Lab.
Semi Anechoic Chamber	No.4
Date	December 5, 2018
Temperature / Humidity	22 deg. C / 51 % RH
Engineer	Hiroyuki Furutaka
Mode	Tx 433.92 MHz

Bandwidth Limit : Fundamental Frequency **433.92** MHz x 0.25% = 1084.80 kHz

* The above limit was calculated from more stringent nominal frequency.

-20dB Bandwidth [kHz]	Bandwidth Limit [kHz]	Result
32.962	1084.80	Pass

99% Occupied Bandwidth [kHz]	Bandwidth Limit [kHz]	Result
32.3656	1084.80	Pass



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APPENDIX 2: Test instruments

Test Instruments

Test item	LIMS ID	Description	Manufacturer	Model	Serial	Last Calibration Date	Calibration Due Date	Cal Int
RE	141545	DIGITAL HiTESTER	HIOKI	3805	51201148	1/9/2018	1/31/2019	12
RE	141508	Horn Antenna 1-18GHz	Schwarzbeck	BBHA9120D	9120D-557	6/8/2018	6/30/2019	12
RE	141506	Horn Antenna 15-40GHz	Schwarzbeck	BBHA9170	BBHA9170307	6/8/2018	6/30/2019	12
RE	142227	Measure	KOMELON	KMC-36	-	-	-	-
RE	141581	MicroWave System Amplifier	AGILENT	83017A	650	10/4/2018	10/31/2019	12
RE	141412	Microwave Cable	Junkosha	MWX221	1305S002R(1m) / 1405S146(5m)	6/14/2018	6/30/2019	12
RE	142011	AC4 Semi Anechoic Chamber(NSA)	TDK	Semi Anechoic Chamber 3m	DA-10005	6/28/2018	6/30/2020	24
RE	141562	Thermo-Hygrometer	CUSTOM	CTH-180	1501	1/24/2018	1/31/2019	12
RE	141901	Spectrum Analyzer	AGILENT	E4440A	MY48250080	10/4/2018	10/31/2019	12
RE	141297	High Pass Filter(1.1-10GHz)	TOKYO KEIKI	TF219CD1	1001	1/18/2018	1/31/2019	12
RE	141152	EMI measurement program	TSJ	TEPTO-DV	-	-	-	-
RE	142017	AC4 Semi Anechoic Chamber(SVSWR)	TDK	Semi Anechoic Chamber 3m	DA-10005	4/7/2018	4/30/2019	12
RE	141583	Pre Amplifier	SONOMA INSTRUMENT	310	260833	2/27/2018	2/28/2019	12
RE	141267	Logperiodic Antenna(200-1000M Hz)	Schwarzbeck	VUSLP9111B	911B-192	6/1/2018	6/30/2019	12
RE	141951	EMI Test Receiver	Rohde & Schwarz	ESR26	101408	1/30/2018	1/31/2019	12
RE	141397	Coaxial Cable	UL Japan	-	-	6/13/2018	6/30/2019	12
RE	148898	Attenuator	KEYSIGHT	8491A	MY52462282	10/3/2018	10/31/2019	12
RE	141425	Biconical Antenna	Schwarzbeck	BBA9106	1302	6/1/2018	6/30/2019	12
RE	142645	Loop Antenna	UL Japan	-	-	-	-	-

*Hyphens for Last Calibration Date, Calibration Due Date and Cal Int (month) are instruments that Calibration is not required (e.g. software), or instruments checked in advance before use.

The expiration date of the calibration is the end of the expired month.

All equipment is calibrated with valid calibrations. Each measurement data is traceable to the national or international standards.

As for some calibrations performed after the tested dates, those test equipment have been controlled by means of an unbroken chains of calibrations.

Test item:

RE: Radiated emission, 99 % Occupied Bandwidth, -20 dB bandwidth, and Automatically deactivate tests

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